				PCN Date:			October 14, 2022		
Title: Qualification of new			w Fab site (FFAB) using qualified Process Technology, Die Revision,					ology, Die Revision,	
Datasheet update			date	and additional Assembly BO		BOM optio	BOM options for select devices		
Cus	stomer (Contact:	<u>P</u>	PCN Manager		Dept:			Quality Services
Proposed 1 st Ship Date: J			Jan 1 3 , 2023		Sample requests accepted until:			Nov 13, 2022*	
*Sa	mple re	equests rece	ived	afte	r November 13, 2	022 will n	ot be	suppo	orted.
Cha	nge Ty	pe:							
	Assem	bly Site			Assembly Process		\square	Assembly Materials	
\boxtimes	Design			Electrical Specification			Mechanical Specification		
Test Site		\boxtimes	Packing/Shipping/Labeling			Test Process			
Wafer Bump Site			Wafer Bump Material			Wafer Bump Process			
Wafer Fab Site		\boxtimes	Wafer Fab Materials		\boxtimes	Wafer	Fab Process		
		Part number change							

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (FFAB, BICOM3XHV) and assembly BOM options (MLA) for selected devices as listed below in the product affected section.

C	urrent Fab Site	3	Additional Fab Site			
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	
SFAB	JIBB	150 mm	FFAB	BICOM3XHV	200 mm	

The die was also changed as a result of the process change.

Assembly BOM options are noted below:

	Current	Additional
Bond wire composition, diameter	Au, 1.15 mils	Cu,1.0 mil
Mold Compound	4209640	4226323
Mount Compound	4205846	4147858

The datasheet will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The link to the revised datasheet is available in the table below.



INA126, INA2126 SBOS062C – SEPTEMBER 2000 – REVISED JANUARY 2022

Changes from Revision B (December 2015) to Revision C (December 2021) Page	
Updated the numbering format for tables, figures, and cross-references throughout the document	
Added dual supply specification to Absolute Maximum Ratings	
• Deleted redundant operating temperature and input common mode voltage specifications in Recommended	
Operating Conditions	
Added dual supply and specified temperature specifications in Recommended Operating Conditions	
Added proper signs for PSRR and input bias current specifications in <i>Electrical Characteristics</i>	
• Deleted V _O = 0 V test condition of common-mode voltage specification in <i>Electrical Characteristics</i>	
 Changed common-mode voltage specification from ±11.25 V minimum, to –11.25 V minimum and 11.25 V 	
maximum, in Electrical Characteristics	
 Changed minimum CMRR specification for INA126U/E, INA2126E from 83 dB to 80 dB in Electrical 	
Characteristics	
 Added typical input bias current specification of ±10 nA for INA126PA/UA/EA and INA2126PA/UA/EA in 	
Electrical Characteristics	
• Changed current noise specifications in <i>Electrical Characteristics</i> from 60 fA/ √Hz to 160 fA/ √Hz for f = 1 kHz,	
and from 2 pApp to 7.3 pApp for f = 0.1 Hz to 10 Hz7	
· Changed test condition for short-circuit current specification in Electrical Characteristics from "Short circuit to	
ground" to "Continuous to V _S / 2" for clarity7	
Changed short-circuit current specification in Electrical Characteristics from +10/-5 mA to ±5 mA7	
 Deleted redundant voltage range, operating temperature range, and specification temperature range 	
specifications from Electrical Characteristics	
• Changed Figures 6-7, 6-10, 6-13, 6-14, 6-15, 6-16, 6-17	
Added Figure 6-11	

Product Family	Current Datasheet Number	New Datasheet Number	Link to full datasheet
INA126, INA2126	SBOS062B	SBOS062C	http://www.ti.com/product/INA126

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-milimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

ſ	RoHS	REACH	Green Status	IEC 62474
	🛛 No Change	🛛 No Change	🛛 No Change	🛛 No Change

Fab Site Information			
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
FR-BIP-1	TID	DEU	Freising
Die Rev: Current	New		
Die Rev [2P]	Die Rev [2P]		
А	Α		
Sample product shipp	ping label (not actual prod	luct label)	
Sample product shipp TEXAS INSTRUMENTS MADE IN: Malaysia 20: 20: MSL '2 /260C/1 YEAR SE MSL 1 /235C/UNLIM 03 OPT: ITEM: 3 LBL: 5A (L)TO:1	G4 G4 AL DT 1/29/04	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 P) 2P) REV: (V) 0033317 201) CS0: SHE (21L) CCO-USA (22L) ASO: MLA (23L) ACO: MYS	
TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SE MSL 1 /235C/UNLIM 03 OPT: ITEM: 3	G4 G4 AL DT 1/29/04	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (311)LOT: 3959047MLA (4W) TKY(1T) 7523483S12 P) 2P) REV: (V) 0033317 20L) CC0:USA	
TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 29: MSL 2 /260C/1 YEAR SE MSL 1 /235C/UNLIM 03 OPT: ITEM: 3 LBL: 5A (L)TO:	G4 G4 AL DT 1/29/04	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA 4W) TKY (1T) 7523483SI2 P) 2P) REV: (V) 0033317 20L) COD: SHE (21L) CCO-USA 22L) ASO: MLA (23L) ACO: MYS	2126UA/2K5

For alternate parts with similar or improved performance, please visit the product page on $\underline{\text{TI.com}}$

Qualification Report

Approve Date 29-Jun-2022

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: INA2126E	QBS Product Reference: INA126U	QBS Process Reference: INA821ID	QBS Process Reference: <u>OPA207ID</u>
HTOL	Life Test, 150C	300 Hours	-	1/77/0	3/231/0	3/231/0
нвм	ESD - HBM	2000V	1/3/0	1/3/0	1/3/0	3/9/0
CDM	ESD - CDM	1000V	1/3/0	1/3/0	-	3/9/0
CDM	ESD - CDM	500V	1/3/0	1/3/0	1/3/0	3/9/0
CDM	ESD - CDM	750V	-	1/3/0	1/3/0	3/9/0
LU	Latch-up, 125C	Per JESD78 Class 1	-	-	-	3/18/0
LU	Latch-up	Per JESD78 Class 2	1/6/0	-	1/6/0	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	3/90/0	3/90/0
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	-	3/231/0	3/231/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	1/77/0	3/231/0	3/231/0
UHAST	Unbiased HAST 130C/85%RH	96 Hours	3/231/0	-	3/231/0	3/231/0

- QBS: Qual By Similarity

- Qual Device INA2126E/EA is qualified at L2, 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

Qualification Report Approve Date 27-JULY -2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: <u>INA2126U</u>	QBS Reference: <u>OPA202ID</u>	QBS Reference: <u>INA828ID</u>	QBS Reference: <u>INA821ID</u>	QBS Reference: <u>OPA207ID</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	3/231/0	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0
тс	A4	Temperature Cycle	-65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/231/0	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	3/231/0	3/231/0
ESD	E2	ESD CDM	-	250 Volts	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD CDM	-	750 Volts	1/3/0	-	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/6/0	-	1/6/0	1/6/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	3/90/0	3/90/0	1/30/0

QBS: Qual By Similarity

- Qual Device INA2126U is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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